查询CDC339供应商

多 <mark>邦,专业PCB打样工厂</mark> ,24小时加急出货	CDC339
CLOCK	DRIVER
WITH 3-STATE O	UTPUTS
SCAS331 – DECEMBER 1992 – REVISED	MARCH 1994

- Low Output Skew, Low Pulse Skew for Clock-Distribution and Clock-Generation Applications
- TTL-Compatible Inputs and Outputs
- Distributes One Clock Input to Eight Outputs
 - Four Same-Frequency Outputs
 - Four Half-Frequency Outputs
- Distributed V_{CC} and Ground Pins Reduce Switching Noise
- High-Drive Outputs (-48-mA I_{OH}, 48-mA I_{OL})
- State-of-the-Art E*PIC-*II*B*™ BiCMOS Design Significantly Reduces Power Dissipation
- Package Options Include Plastic Small-Outline (DW) and Shrink Small-Outline (DB) Packages

(TOP VIEW)						
\Box		- 5				
1	20] Y2				
		GND				
] Y1				
4	17] V _{CC}				
5] CLK				
6] GND				
7	14]∨ _{cc}				
8	13] Q1				
9	12] GND				
10	11] Q2				
	1 2 3 4 5 6 7 8 9	1 20 2 19 3 18 4 17 5 16 6 15 7 14 8 13 9 12				

description

The CDC339 is a high-performance, low-skew clock driver. It is specifically designed for applications requiring synchronized output signals at both the primary clock frequency and one-half the primary clock frequency. The four Y outputs switch in phase and at the same frequency as the clock (CLK) input. The four Q outputs switch at one-half the frequency of CLK.

When the output-enable (\overline{OE}) input is low and the clear (\overline{CLR}) input is high, the Y outputs follow CLK and the Q outputs toggle on low-to-high transitions of CLK. Taking \overline{CLR} low asynchronously resets the Q outputs to the low level. When \overline{OE} is high, the outputs are in the high-impedance state.

The CDC339 is characterized for operation from -40° C to 85° C.

1000	FUN	CHONI	ADLE		
INPUTS			OUTPUTS		
OE	CLR	CLK	Y1-Y4	Q1-Q4	
Н	Х	Х	Z	Z	
L	L	L	L	L	
L	L	Н	н	L	
L	Н	L	L	Q ₀ †	
L	Н	\uparrow	н		

[†]The level of the Q outputs before the indicated steady-state input conditions were established.



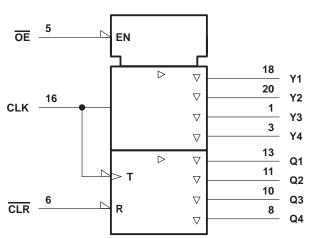
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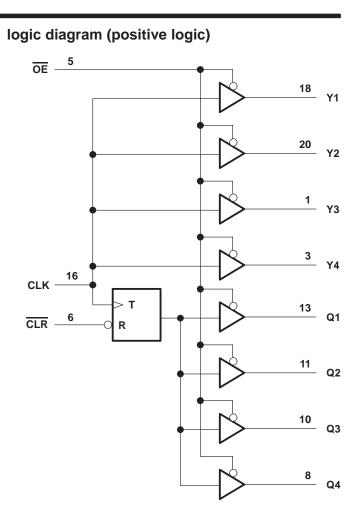


CDC339 CLOCK DRIVER WITH 3-STATE OUTPUTS SCAS331 – DECEMBER 1992 – REVISED MARCH 1994

logic symbol[†]



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[‡]

Supply voltage range, V _{CC}	
Voltage range applied to any output in the disabled or power-off state, Vo	5 V to 5.5 V
Current into any output in the low state, Io	96 mA
Input clamp current, I _{IK} (V _I < 0)	–18 mA
Output clamp current, I _{OK} (V _O < 0)	. –50 mA
Maximum power dissipation at T _A = 55°C (in still air) (see Note 2): DB package	0.6 W
DW package	1.6 W
Storage temperature range, T _{stg}	C to 150°C

[‡] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

2. The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 750 mils. For more information, refer to the *Package Thermal Considerations* application note in the 1994 *ABT Advanced BiCMOS Technology Data Book*, literature number SCBD002B.



recommended operating conditions (see Note 3)

		MIN	MAX	UNIT
VCC	Supply voltage	4.75	5.25	V
VIH	High-level input voltage	2		V
VIL	Low-level input voltage		0.8	V
VI	Input voltage	0	VCC	V
ЮН	High-level output current		-48	mA
IOL	Low-level output current		48	mA
fclock	Input clock frequency		80	MHz
ТА	Operating free-air temperature	-40	85	°C

NOTE 3: Unused pins (input or I/O) must be held high or low.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS		MIN	ΤΥΡ [†] ΜΑΧ	UNIT
VIK	V _{CC} = 4.75 V,	l _l = -18 mA			-1.2	V
VOH	V _{CC} = 4.75 V,	I _{OH} = - 48 mA		2		V
VOL	V _{CC} = 4.75 V,	I _{OL} = 48 mA			0.5	V
IIН	V _{CC} = 5.25 V,	V _I = 2.7 V			50	μΑ
١ _{١L}	V _{CC} = 5.25 V,	V _I = 0.5 V			-50	μΑ
IOZ	V _{CC} = 5.25 V,	V_{O} = 2.7 V or 0.5 V			±50	μΑ
IO‡	V _{CC} = 5.25 V,	$V_{O} = 2.5 V$		-50	-180	mA
			Outputs high		70	
Icc	$V_{CC} = 5.25 \text{ V}, V_{O} = 100000000000000000000000000000000000$	$I_{O} = 0,$	Outputs low		85	mA
			Outputs disabled		70	
Ci	VI = 2.5 V or 0.5 V				3	pF
Co	$V_{O} = 2.5 \text{ V or } 0.5 \text{ V}$				8	pF

[†] All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

[‡]Not more than one output should be tested at a time, and the duration of the test should not exceed one second.

timing requirements over recommended ranges of supply voltage and operating free-air temperature

				MAX	UNIT
fclock	Clock frequency	frequency			MHz
		CLR low	4		
tw	Pulse duration	CLK low	4		ns
		CLK high	4		
t _{su}	Setup time	CLR inactive before CLK↑	2		ns
	Clock duty cycle		40%	60%	

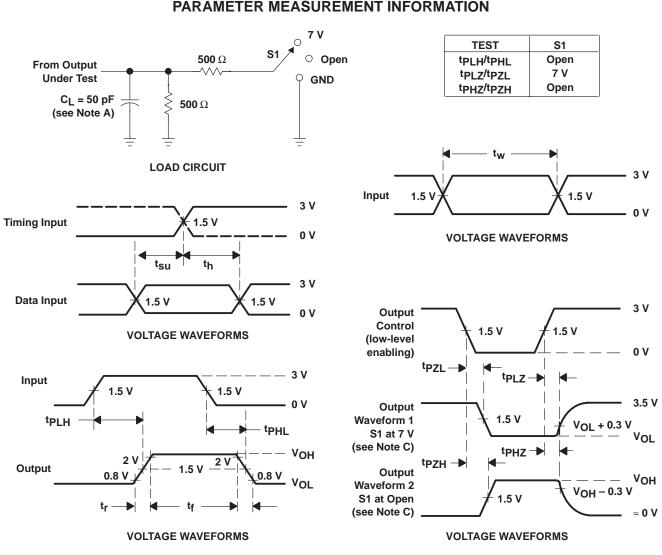


switching characteristics over recommended ranges of supply voltage and operating free-air temperature (see Figures 1 and 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	MIN TYPT	МАХ	UNIT
f _{max}			80		MHz
^t PLH	CLK	Any Y or Q	3	9	ns
^t PHL			3	9	
^t PHL	CLR	Any Q	4	9	ns
^t PZH	ŌĒ	Any Y or Q	2	7	ns
^t PZL			3	7	
^t PHZ			2	7	
^t PLZ	ŌE	Any Y or Q	2	7	ns
	CLK↑	Υ↑		0.75	
^t sk(o)		Q↑		0.9	ns
		Y↑ and Q↑		0.9	
tr			0.9		ns
tf			0.7		ns

[†] All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.





PARAMETER MEASUREMENT INFORMATION

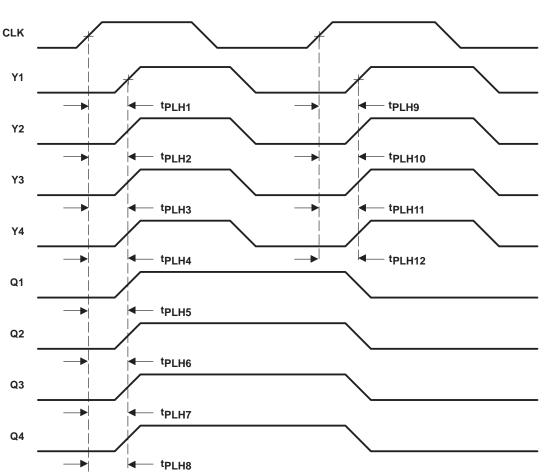
NOTES: A. Cl includes probe and jig capacitance.

- B. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, Z_O = 50 Ω , t_f \leq 2.5 ns, t_f \leq 2.5 ns.
- C. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- D. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



CDC339 **CLOCK DRIVER** WITH 3-STATE OUTPUTS SCAS331 - DECEMBER 1992 - REVISED MARCH 1994



PARAMETER MEASUREMENT INFORMATION

- NOTES: A. Output skew, t_{Sk(0)}, from CLK↑ to Y↑, is calculated as the greater of the difference between the fastest and slowest of t_{PLHn} (n = 1, 2, 3, 4) or t_{PLHn} (n = 9, 10, 11, 12).
 B. Output skew, t_{Sk(0)}, from CLK↑ to Q↑, is calculated as the greater of the difference between the fastest and slowest of t_{PLHn} (n = 5, 6, 7, 8).
 C. Output skew t t_{ob} form CLK↑ to Y↑ and O↑ is calculated as the greater of the difference between the fastest and slowest of t_{PLHn} (n = 5, 6, 7, 8).
 - C. Output skew, $t_{sk(0)}$, from CLK¹ to Y¹ and Q¹, is calculated as the greater of the difference between the fastest and slowest of t_{PLHn} (n = 1, 2, ..., 8).

Figure 2. Skew Waveforms and Calculations



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